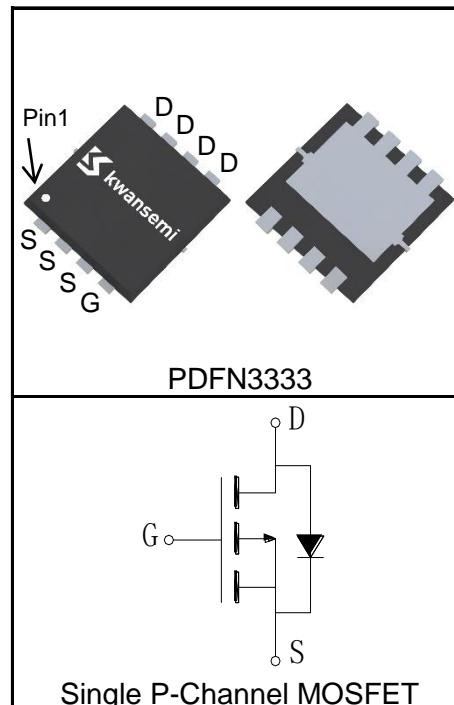


Features

- -30V/-38A,
 $R_{DS(ON)} = 11\text{m}\Omega$ (Typ.)@ $V_{GS}=-10\text{V}$
- $R_{DS(ON)} = 16\text{m}\Omega$ (Typ.)@ $V_{GS}=-4.5\text{V}$
- Low $R_{DS(ON)}$
- Super High Dense Cell Design
- Fast Switching Speed
- 100% Avalanche Tested
- 100% Rg Tested

Pin Description



Applications

- Switching Application Systems



Halogen-Free

Absolute Maximum Ratings

Symbol	Parameter	Rating	Unit
Common Ratings ($T_c=25^\circ\text{C}$ Unless Otherwise Noted)			
V_{DSS}	Drain-Source Voltage	-30	V
V_{GSS}	Gate-Source Voltage	± 25	
T_{Jmax}	Maximum Junction Temperature	150	$^\circ\text{C}$
T_J, T_{STG}	Operating and Storage Temperature Range	-55 to 150	$^\circ\text{C}$
I_S	Diode Continuous Forward Current	$T_c=25^\circ\text{C}$	-38
			A

Mounted on Large Heat Sink

$I_{DP}^{(1)}$	300 μs Pulse Drain Current Tested	$T_c=25^\circ\text{C}$	-152	A
$I_D^{(2)}$	Continuous Drain Current@ $T_c(V_{GS}=-10\text{V})$	$T_c=25^\circ\text{C}$	-38	A
		$T_c=100^\circ\text{C}$	-24	
	Continuous Drain Current@ $T_A(V_{GS}=-10\text{V})^{(3)}$	$T_A=25^\circ\text{C}$	-13	
		$T_A=70^\circ\text{C}$	-10	
P_D	Maximum Power Dissipation@ T_c	$T_c=25^\circ\text{C}$	32	W
		$T_c=100^\circ\text{C}$	13	
	Maximum Power Dissipation@ $T_A^{(3)}$	$T_A=25^\circ\text{C}$	3.5	
		$T_A=70^\circ\text{C}$	2.3	

Symbol	Parameter	Rating	Unit
$R_{\theta JC}$	Thermal Resistance-Junction to Case	3.95	°C/W
$R_{\theta JA}^{(3)}$	Thermal Resistance-Junction to Ambient	35	°C/W
Drain-Source Avalanche Ratings			
$E_{AS}^{(4)}$	Avalanche Energy, Single Pulsed	132	mJ

Electrical Characteristics ($T_C=25^\circ C$ Unless Otherwise Noted)

Symbol	Parameter	Test Condition	KS3313MA			Unit
			Min.	Typ.	Max.	

Static Characteristics

BV_{DSS}	Drain-Source Breakdown Voltage	$V_{GS}=0V, I_{DS}=-250\mu A$	-30			V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS}=-30V, V_{GS}=0V$			-1	μA
		$T_J=125^\circ C$			-30	
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_{DS}=-250\mu A$	-1.1	-1.6	-2.3	V
I_{GSS}	Gate Leakage Current	$V_{GS}=\pm 25V, V_{DS}=0V$			± 100	nA
$R_{DS(ON)}^{(5)}$	Drain-Source On-state Resistance	$V_{GS}=-10V, I_{DS}=-18A$		11	13	$m\Omega$
		$V_{GS}=-4.5V, I_{DS}=-14A$		16	21	$m\Omega$

Diode Characteristics

$V_{SD}^{(5)}$	Diode Forward Voltage	$I_{SD}=-20A, V_{GS}=0V$		-0.89	-1.2	V
t_{rr}	Reverse Recovery Time	$I_{SD}=-20A, dI_{SD}/dt=100A/\mu s$		44		ns
Q_{rr}	Reverse Recovery Charge			29		nC

Dynamic Characteristics⁽⁶⁾

R_G	Gate Resistance	$V_{GS}=0V, V_{DS}=0V, F=1MHz$		18		Ω
C_{iss}	Input Capacitance	$V_{GS}=0V,$ $V_{DS}=-15V,$ Frequency=1.0MHz		1640		pF
C_{oss}	Output Capacitance			245		
C_{rss}	Reverse Transfer Capacitance			190		
$t_{d(ON)}$	Turn-on Delay Time	$V_{DD}=-15V, I_{DS}=-20A,$ $V_{GS}=-10V, R_G=3\Omega$		11		ns
t_r	Turn-on Rise Time			23		
$t_{d(OFF)}$	Turn-off Delay Time			38		
t_f	Turn-off Fall Time			10		

Gate Charge Characteristics⁽⁶⁾

Q_g	Total Gate Charge	$V_{DS}=-15V, V_{GS}=-10V,$		29		nC
Q_{gs}	Gate-Source Charge	$I_{DS}=-20A$		6		
Q_{gd}	Gate-Drain Charge			7		

Notes:

- ①Pulse width limited by safe operating area.
- ②Calculated continuous current based on maximum allowable junction temperature.
- ③When mounted on 1 inch square copper board, $t \leq 10\text{sec}$.
- ④Limited by $T_{J\max}$, Starting $T_J = 25^\circ\text{C}$, $I_{AS\max} = -23\text{A}$, $L = 0.5\text{mH}$, $V_{DD} = -20\text{V}$, $R_G = 25\Omega$, $V_{GS} = -10\text{V}$.Part not recommended for use above this value.100% Final Test at $I_{AS} = -12\text{A}$, $L = 0.5\text{mH}$.
- ⑤Pulse test;Pulse width $\leq 300\mu\text{s}$, duty cycle $\leq 2\%$.
- ⑥Guaranteed by design, not subject to production testing.

Ordering and Marking Information

Device	Package	Packaging	Quantity	Reel Size	Tape width
KS3313MA	PDFN3333	Tape&Reel	5000	13"	12mm

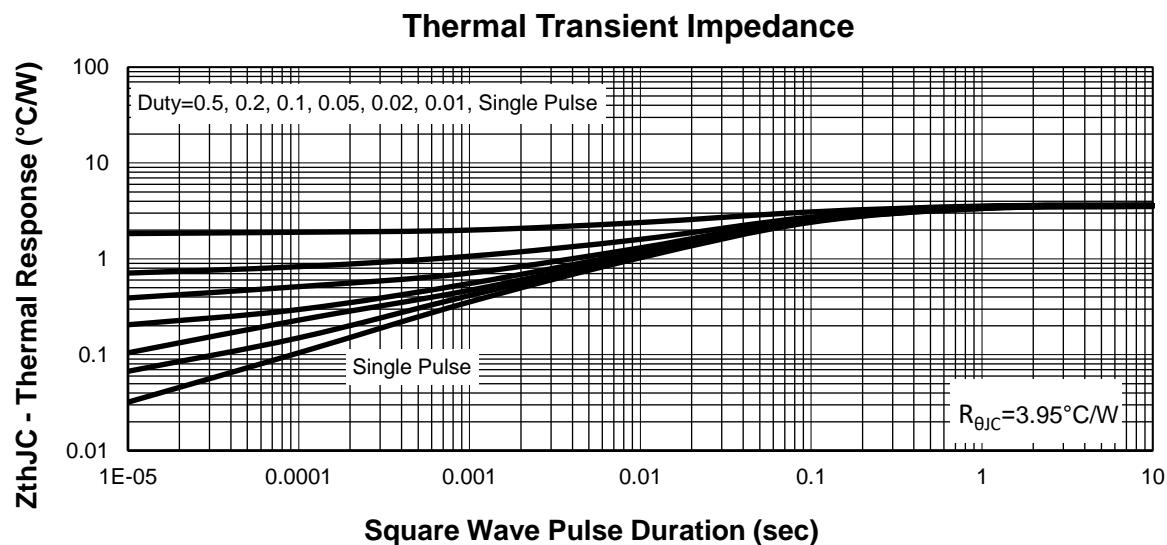
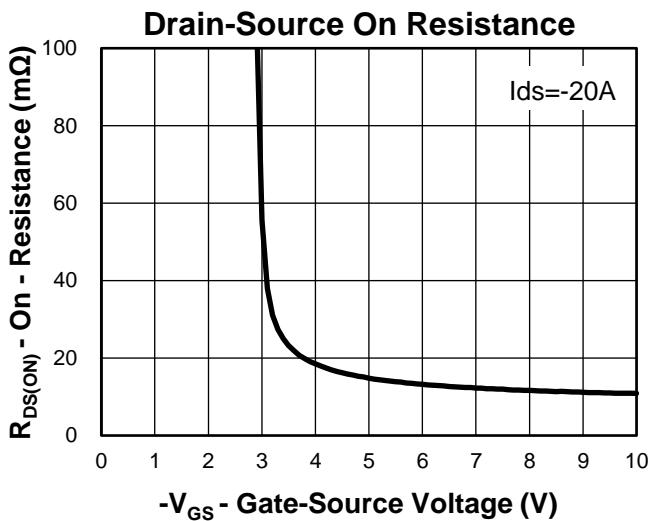
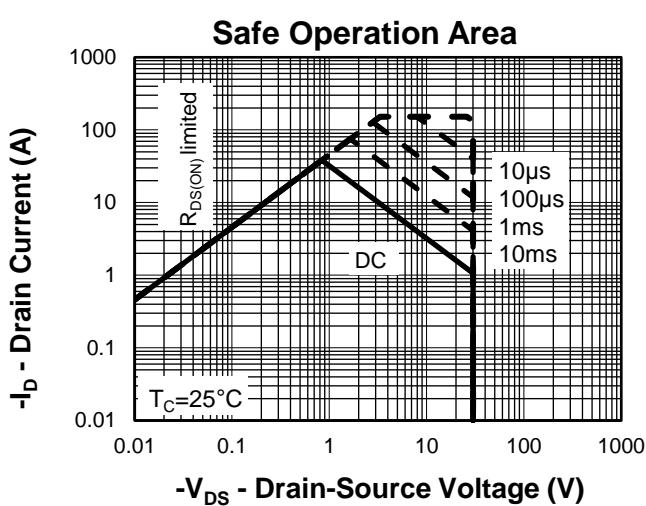
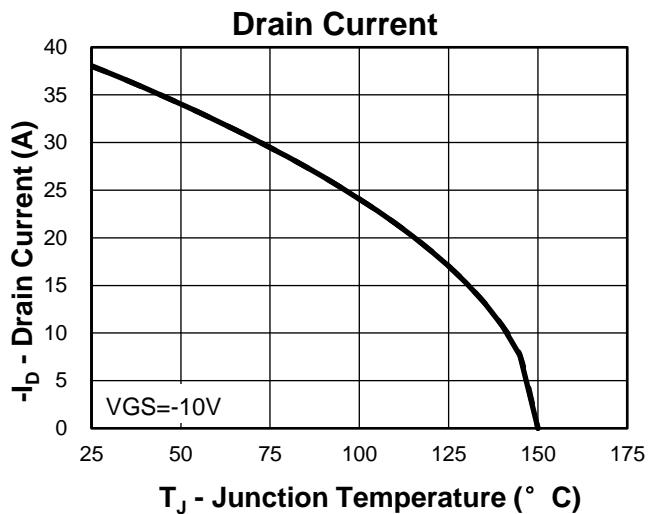
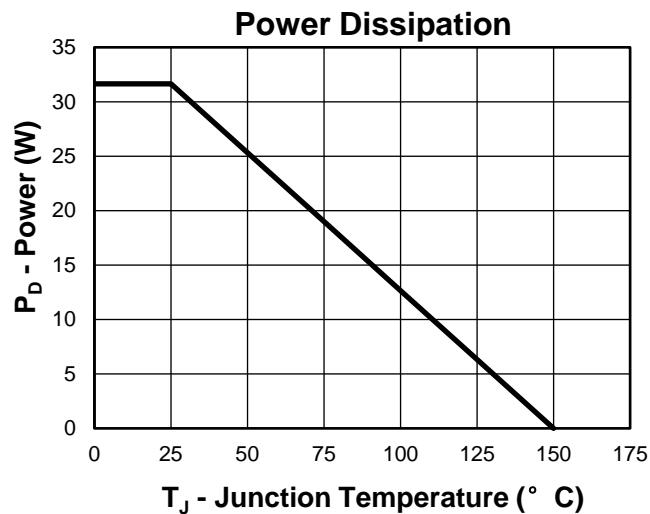


1st Line: Kwansemi Code(KS)

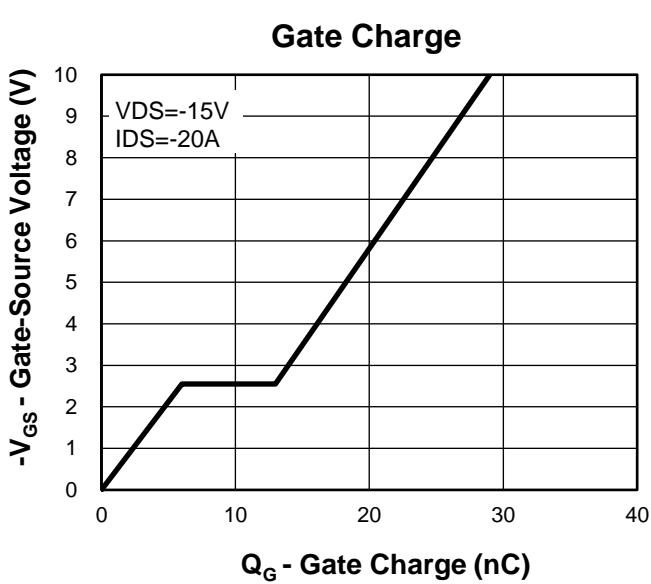
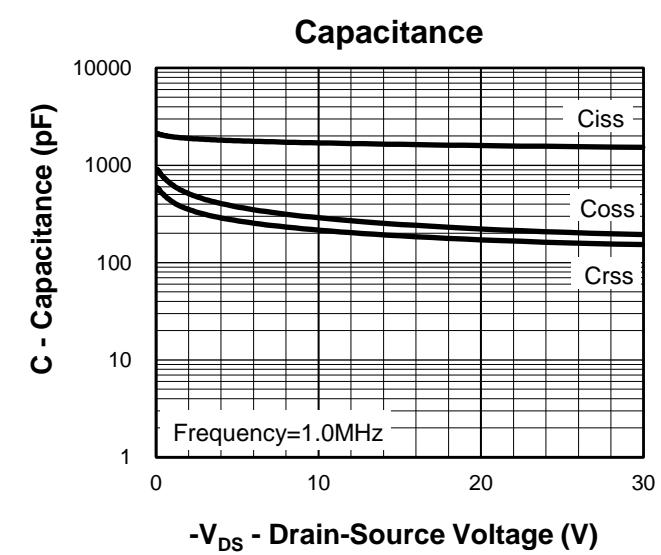
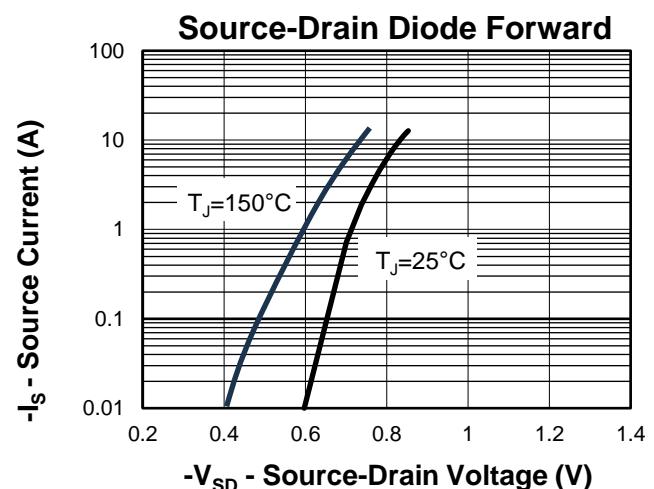
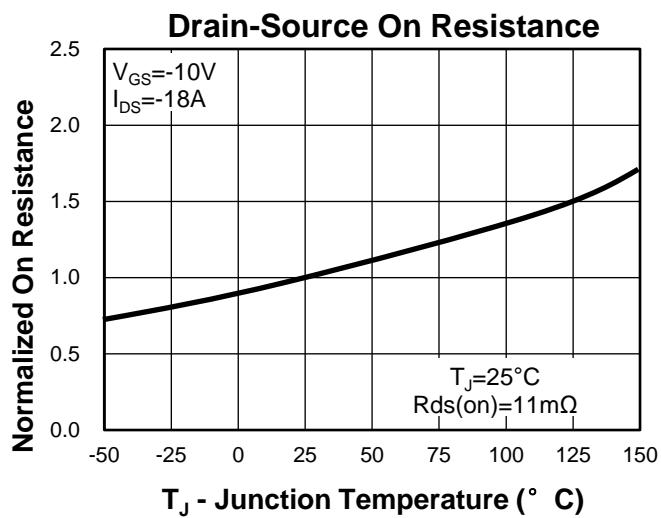
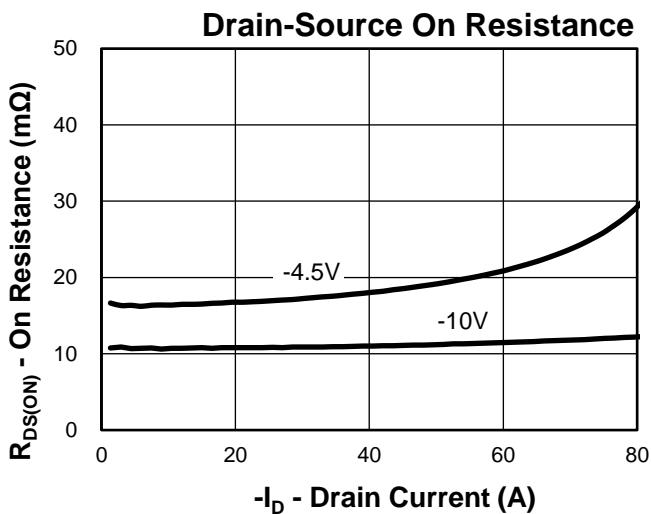
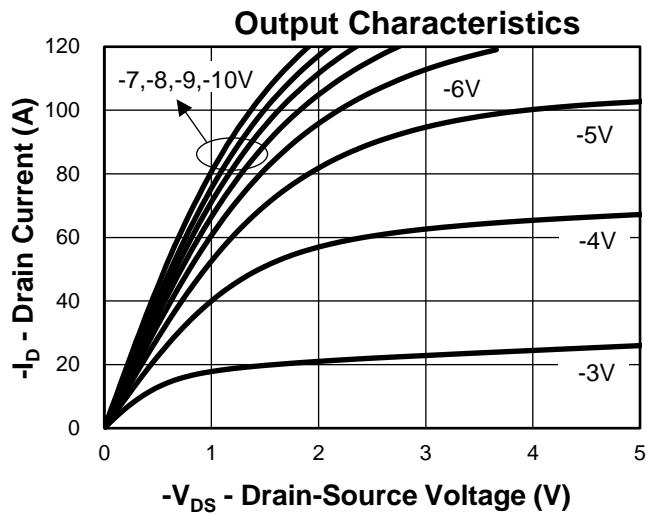
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3rd Line: Lot Number(YWWXXX)

Typical Characteristics

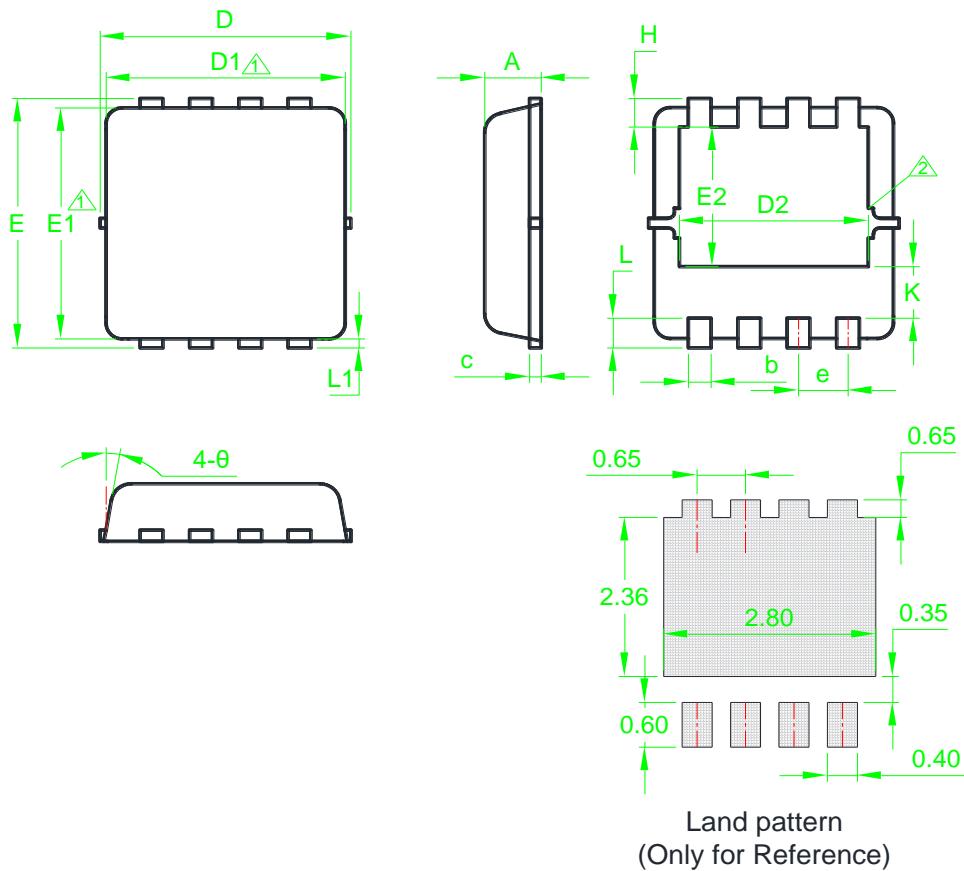


Typical Characteristics



Package Information

PDFN3333

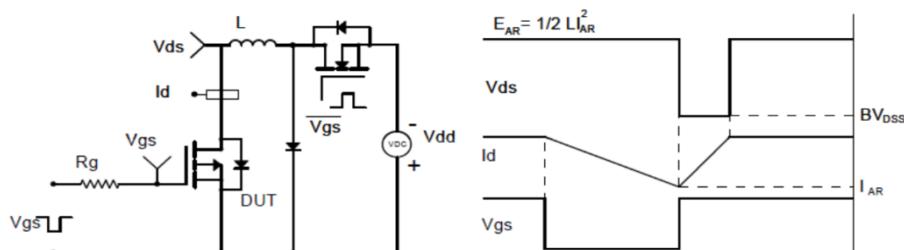


SYMBOL	MM			INCH			SYMBOL	MM			INCH		
	MIN	NOM	MAX	MIN	NOM	MAX	E2	MIN	NOM	MAX	MIN	NOM	MAX
A	0.70	0.80	0.90	0.028	0.031	0.035	e	1.40	*	1.95	0.055	*	0.077
b	0.25	0.30	0.35	0.010	0.012	0.014	H	0.30	0.40	0.50	0.012	0.016	0.020
c	0.10	0.20	0.30	0.004	0.008	0.012	K	0.50	*	*	0.020	*	*
D	3.20	3.30	3.40	0.126	0.130	0.134	L	0.30	0.40	0.50	0.012	0.016	0.020
D1	3.00	3.10	3.20	0.118	0.122	0.126	L1	0.15BSC			0.006BSC		
D2	2.35	2.45	2.55	0.093	0.096	0.100	θ	6°	*	12°	6°	*	12°
E	3.20	3.30	3.40	0.126	0.130	0.134							
E1	2.90	3.05	3.20	0.114	0.120	0.126							

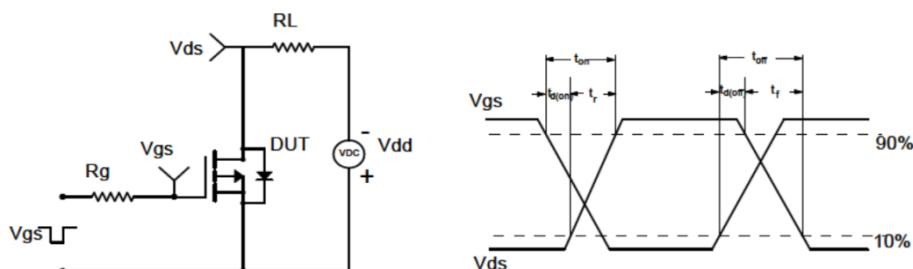
 **1** Dimensions D1 and E1 do not include mold flash protrusions or gate burrs.

 **2** The size and shape of exposed pad are variable depending on mold.

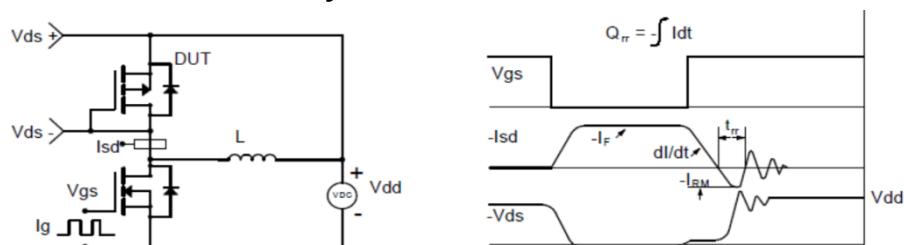
Avalanche Test Circuit and Waveforms



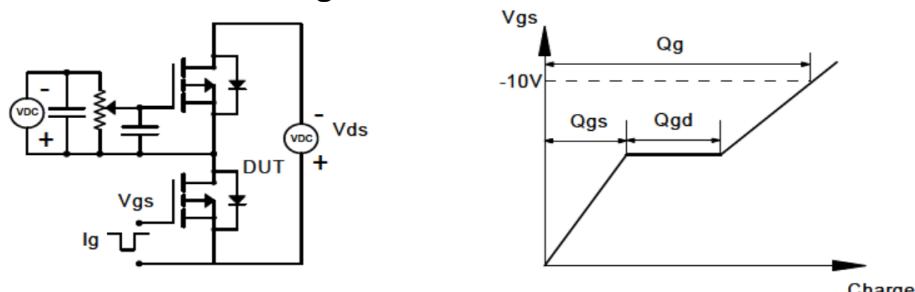
Switching Time Test Circuit and Waveforms



Diode Recovery Test Circuit and Waveforms



Gate Charge Test Circuit and Waveform



Customer Service

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